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Semiconductor devices - Micro-electromechanical devices - Part 1: Terms and definitions

Táto norma obsahuje anglickú verziu európskej normy.
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 09/16

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NORME EUROPÉENNE
EUROPÄISCHE NORM

EN 62047-1

April 2016

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Supersedes EN 62047-1:2006

English Version

**Semiconductor devices - Micro-electromechanical devices - Part
1: Terms and definitions
(IEC 62047-1:2016)**

Dispositifs à semi-conducteurs - Dispositifs
microélectromécaniques - Partie 1: Termes et définitions
(IEC 62047-1:2016)

Halbleiterbauelemente - Bauelemente der
Mikrosystemtechnik - Teil 1: Begriffe
(IEC 62047-1:2016)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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European foreword

The text of document 47F/232/FDIS, future edition 2 of IEC 62047-1, prepared by SC 47F "Microelectromechanical systems" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62047-1:2016.

The following dates are fixed:

- latest date by which the document has to be (dop) 2016-11-10
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In the official version, for Bibliography, the following note has to be added for the standard indicated:

IEC 62047-1:2005

NOTE Harmonized as EN 62047-1:2006.



IEC 62047-1

Edition 2.0 2016-01

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Semiconductor devices – Micro-electromechanical devices –
Part 1: Terms and definitions**

**Dispositifs à semiconducteurs – Dispositifs microélectromécaniques –
Partie 1: Termes et définitions**



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INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Semiconductor devices – Micro-electromechanical devices –
Part 1: Terms and definitions**

**Dispositifs à semiconducteurs – Dispositifs microélectromécaniques –
Partie 1: Termes et définitions**

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International Standard IEC 62047-1 has been prepared by subcommittee 47F: Micro-electromechanical systems, of IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 2005. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) removal of ten terms;
- b) revision of twelve terms;
- c) addition of sixteen new terms.

The text of this standard is based on the following documents:

FDIS	Report on voting
47F/232/FDIS	47F/238/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62047 series, published under the general title *Semiconductor devices – Micro-electromechanical devices*, can be found on the IEC website.

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SEMICONDUCTOR DEVICES – MICRO-ELECTROMECHANICAL DEVICES –

Part 1: Terms and definitions

1 Scope

This part of IEC 62047 defines terms for micro-electromechanical devices including the process of production of such devices.

koniec náhľadu – text ďalej pokračuje v platenej verzii STN